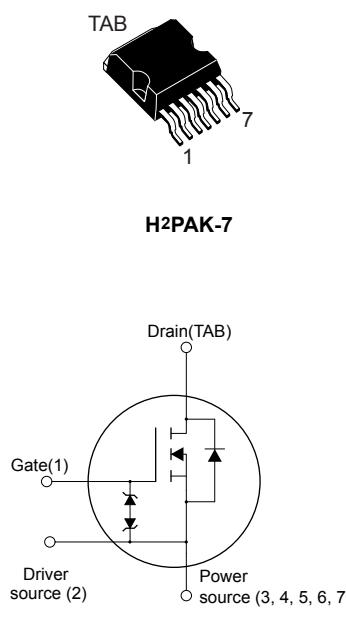


Automotive-grade N-channel 650 V, 102 mΩ typ., 28 A MDmesh DM6 Power MOSFET in an H²PAK-7 package



Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|-----------------|-----------------|--------------------------|----------------|
| STH30N65DM6-7AG | 650 V | 115 mΩ | 28 A |

- AEC-Q101 qualified
- Fast-recovery body diode
- Lower R_{DS(on)} per area vs previous generation
- Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected



Applications

- Switching applications

Description

This high-voltage N-channel Power MOSFET is part of the MDmesh DM6 fast-recovery diode series. Compared with the previous MDmesh fast generation, DM6 combines very low recovery charge (Q_{rr}), recovery time (t_{rr}) and excellent improvement in R_{DS(on)} per area with one of the most effective switching behaviors available in the market for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.

Product status link

[STH30N65DM6-7AG](#)

Product summary

| | |
|------------|----------------------|
| Order code | STH30N65DM6-7AG |
| Marking | 30N65DM6 |
| Package | H ² PAK-7 |
| Packing | Tape and reel |

1

Electrical ratings

Table 1. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|------------|------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 28 | A |
| I_D | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 18 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 112 | A |
| P_{TOT} | Total power dissipation at $T_C = 25^\circ\text{C}$ | 223 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 100 | V/ns |
| $di/dt^{(2)}$ | Peak diode recovery current slope | 1000 | A/ μs |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 100 | V/ns |
| T_J | Operating junction temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_{stg} | Storage temperature range | | $^\circ\text{C}$ |

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 28 \text{ A}$, $V_{DS} (\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 400 \text{ V}$.
3. $V_{DS} \leq 520 \text{ V}$.

Table 2. Thermal data

| Symbol | Parameter | Value | Unit |
|------------------|---------------------------------------|-------|---------------------------|
| R_{thJC} | Thermal resistance, junction-to-case | 0.56 | $^\circ\text{C}/\text{W}$ |
| $R_{thJB}^{(1)}$ | Thermal resistance, junction-to-board | 30 | $^\circ\text{C}/\text{W}$ |

1. When mounted on FR-4 board of 1 inch², 2 oz Cu.

Table 3. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max) | 4 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 100 \text{ V}$) | 600 | mJ |

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified.

Table 4. On/off-state

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-----------------------------------|--|------|------|---------|------------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$ | | | 5 | μA |
| | | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$ ⁽¹⁾ | | | 200 | μA |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$ | | | ± 5 | μA |
| $V_{GS(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ | 3.25 | 4.00 | 4.75 | V |
| $R_{\text{DS(on)}}$ | Static drain-source on-resistance | $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$ | | 102 | 115 | $\text{m}\Omega$ |

1. Defined by design, not subject to production test.

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-------------------------------|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ | - | 2000 | - | pF |
| C_{oss} | Output capacitance | | - | 130 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 1.5 | - | pF |
| $C_{oss \text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0 \text{ to } 520 \text{ V}, V_{GS} = 0 \text{ V}$ | - | 339 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 \text{ MHz}, \text{open drain}$ | - | 1.6 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520 \text{ V}, I_D = 28 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior) | - | 46 | - | nC |
| Q_{gs} | Gate-source charge | | - | 13.5 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 20 | - | nC |

1. $C_{oss \text{ eq.}}$ is defined as the constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|--|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 325 \text{ V}, I_D = 14 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform) | - | 17 | - | ns |
| t_r | Rise time | | - | 3.3 | - | ns |
| $t_{d(off)}$ | Turn-off delay time | | - | 46 | - | ns |
| t_f | Fall time | | - | 8 | - | ns |

Table 7. Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|--|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 28 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 112 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 28 \text{ A}, V_{GS} = 0 \text{ V}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 28 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}$ | - | 126 | | ns |
| Q_{rr} | Reverse recovery charge | (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 0.63 | | μC |
| I_{RRM} | Reverse recovery current | | - | 10 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 28 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$ | - | 220 | | ns |
| Q_{rr} | Reverse recovery charge | (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 2.1 | | μC |
| I_{RRM} | Reverse recovery current | | - | 19 | | A |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

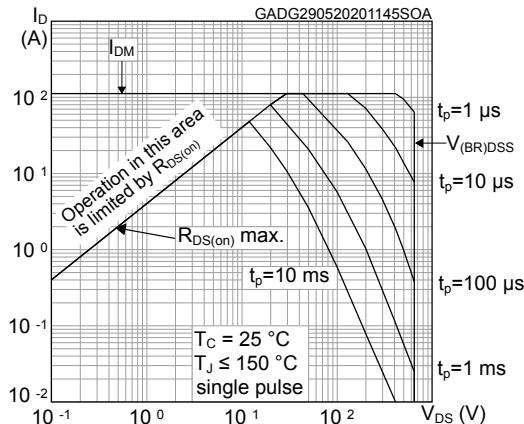
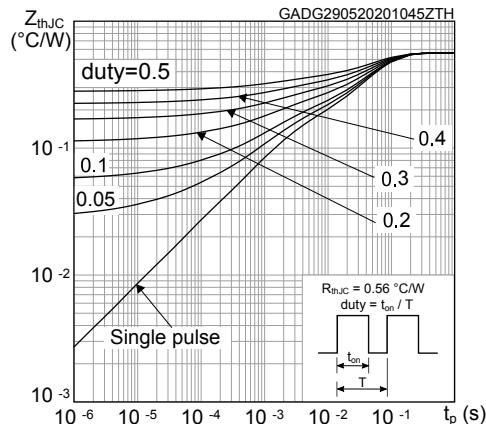
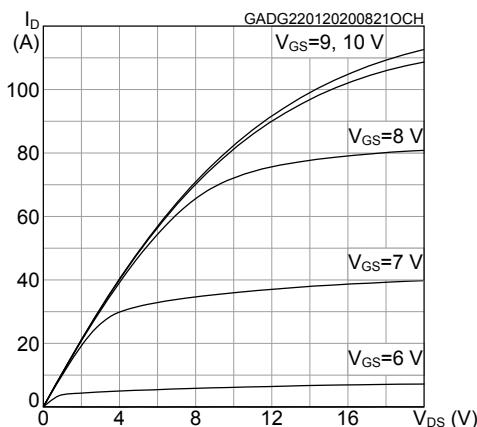
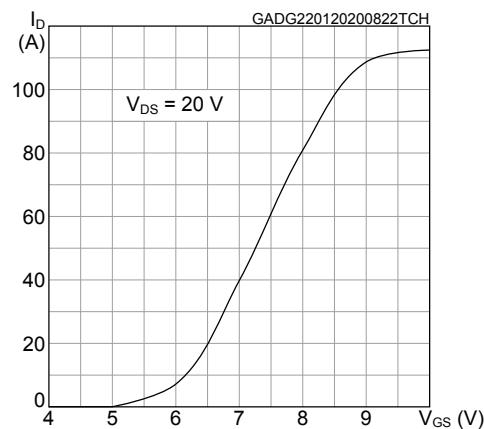
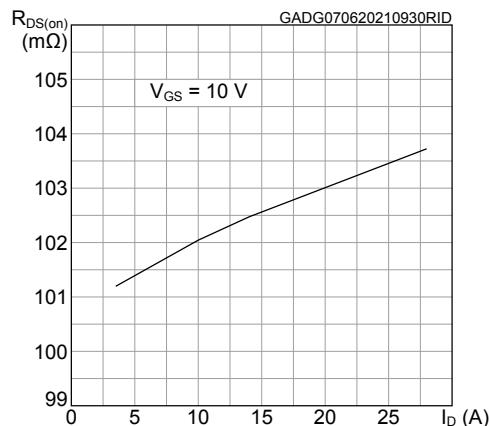
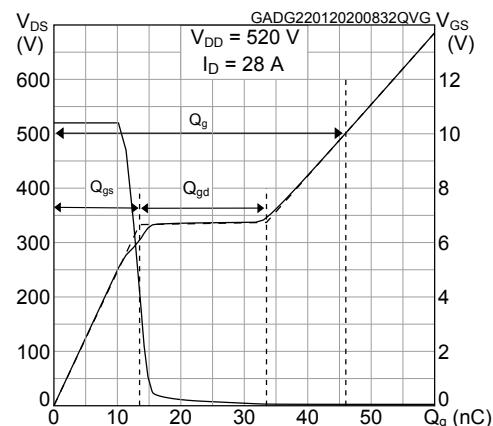
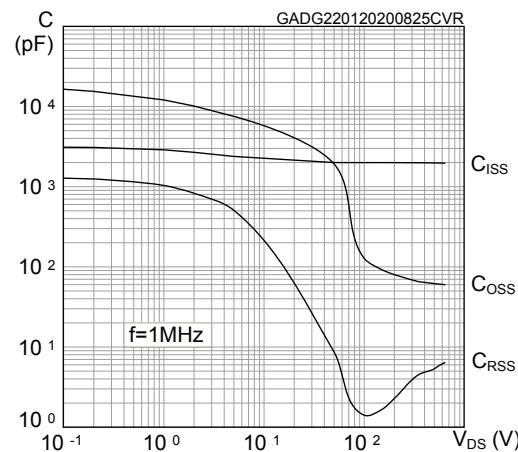
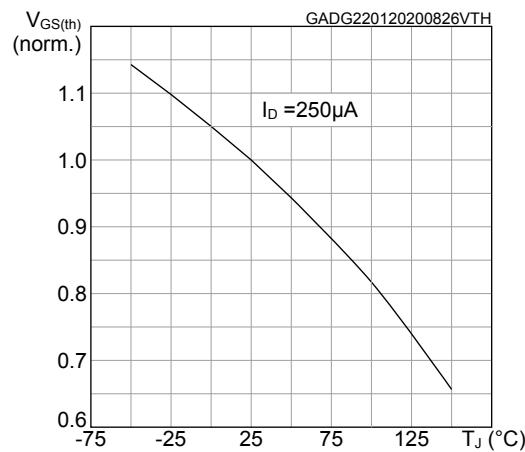
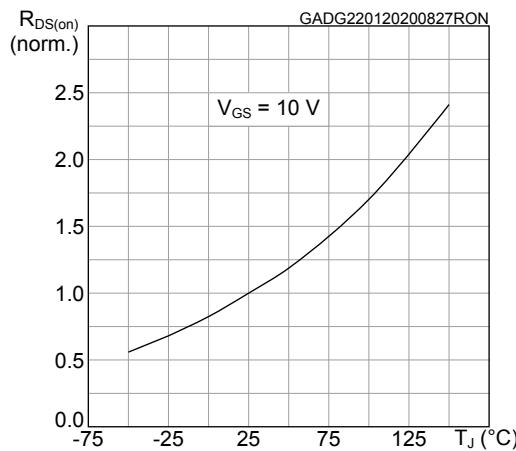
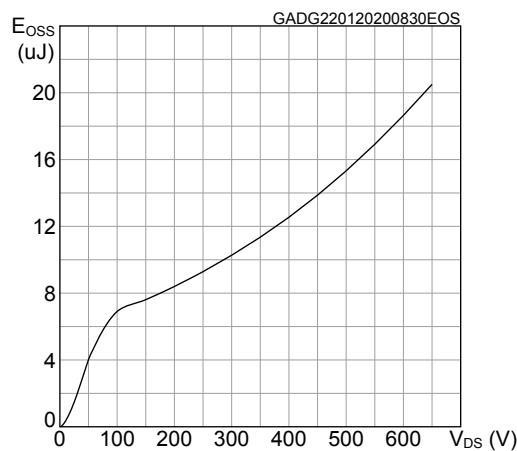
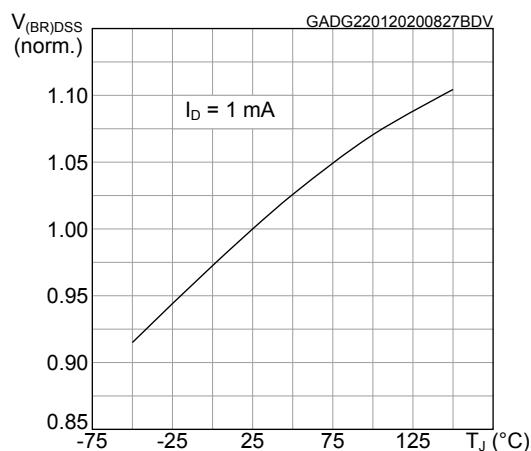
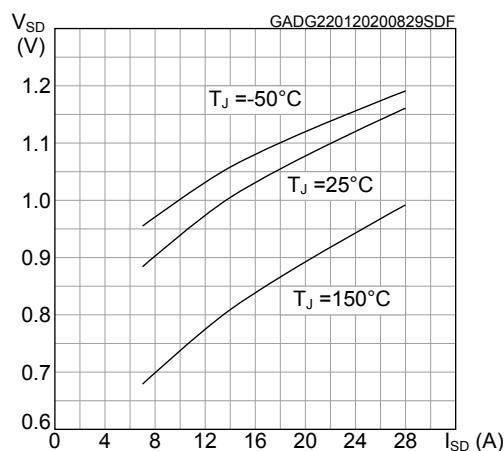
Figure 1. Safe operating area

Figure 2. Maximum transient thermal impedance

Figure 3. Typical output characteristics

Figure 4. Typical transfer characteristics

Figure 5. Typical drain-source on-resistance

Figure 6. Typical gate charge characteristics


Figure 7. Typical capacitance characteristics

Figure 8. Normalized gate threshold vs temperature

Figure 9. Normalized on-resistance vs temperature

Figure 10. Typical output capacitance stored energy

Figure 11. Normalized breakdown voltage vs temperature

Figure 12. Typical reverse diode forward characteristics


3 Test circuits

Figure 13. Switching times test circuit for resistive load

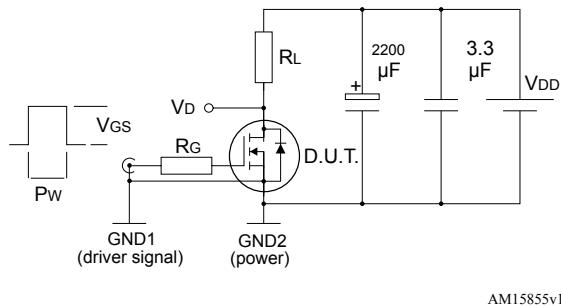


Figure 14. Test circuit for gate charge behavior

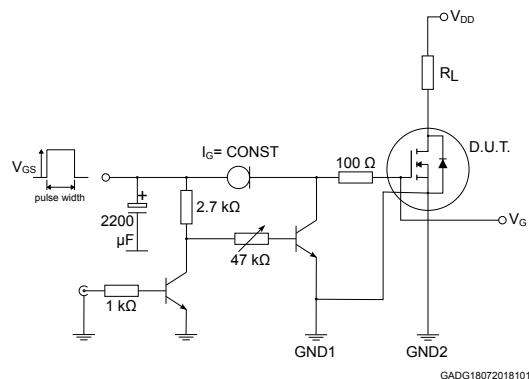


Figure 15. Test circuit for inductive load switching and diode recovery times

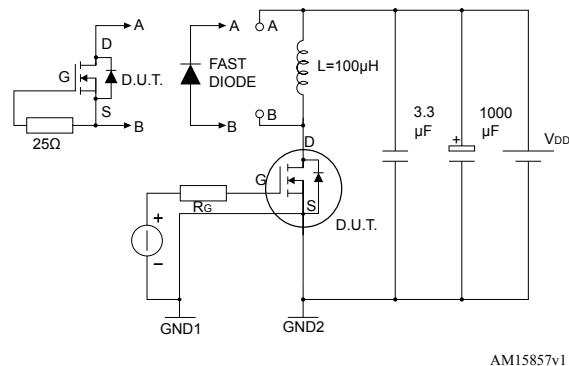


Figure 16. Unclamped inductive load test circuit

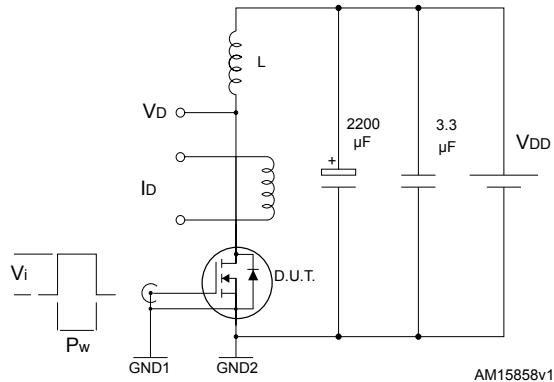


Figure 17. Unclamped inductive waveform

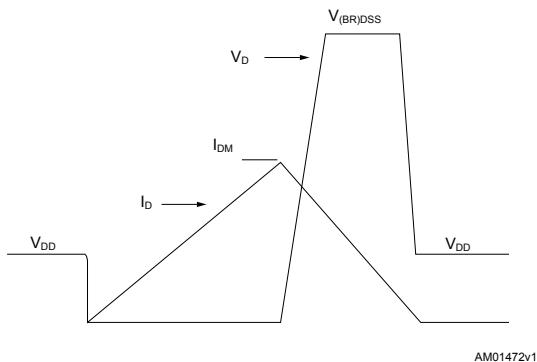
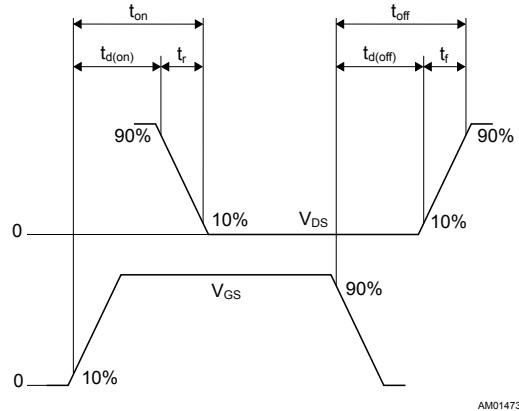


Figure 18. Switching time waveform

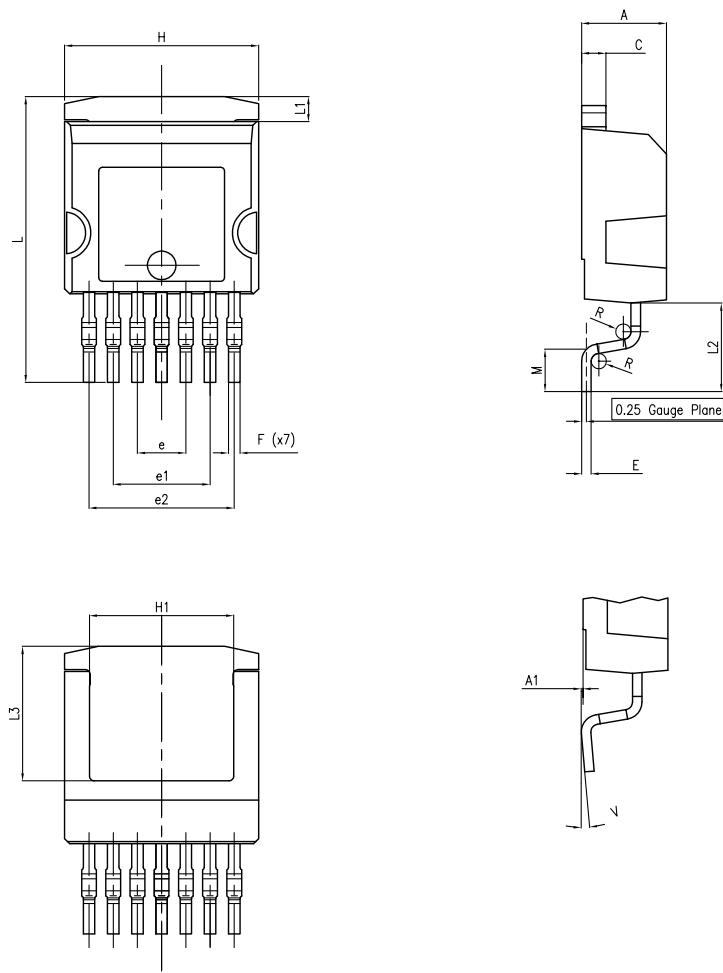


4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 H²PAK-7 package information

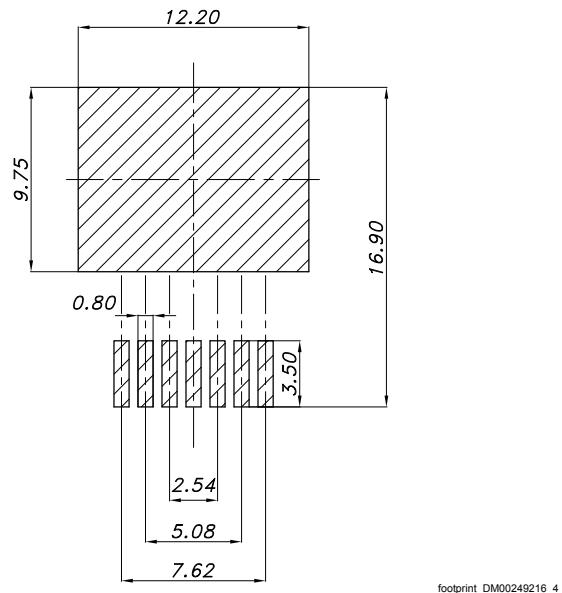
Figure 19. H²PAK-7 package outline



DM00249216_4

Table 8. H²PAK-7 package mechanical data

| Dim. | mm | |
|------|-------|-------|
| | Min. | Max. |
| A | 4.30 | 4.80 |
| A1 | 0.03 | 0.20 |
| C | 1.17 | 1.37 |
| e | 2.34 | 2.74 |
| e1 | 4.88 | 5.28 |
| e2 | 7.42 | 7.82 |
| E | 0.45 | 0.60 |
| F | 0.50 | 0.70 |
| H | 10.00 | 10.40 |
| H1 | 7.40 | 7.60 |
| L | 14.75 | 15.25 |
| L1 | 1.27 | 1.40 |
| L2 | 4.35 | 4.95 |
| L3 | 6.85 | 7.25 |
| M | 1.90 | 2.50 |
| R | 0.20 | 0.60 |
| V | 0° | 8° |

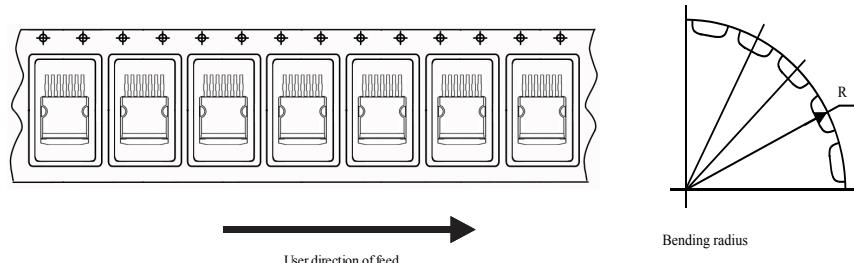
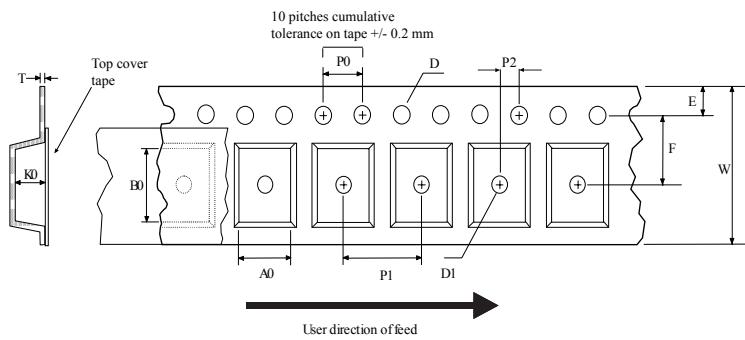
Figure 20. H²PAK-7 recommended footprint

footprint_DM00249216_4

Note: Dimensions are in mm.

4.2 Packing information

Figure 21. Tape outline



GADG160620211017SA

Figure 22. Reel outline

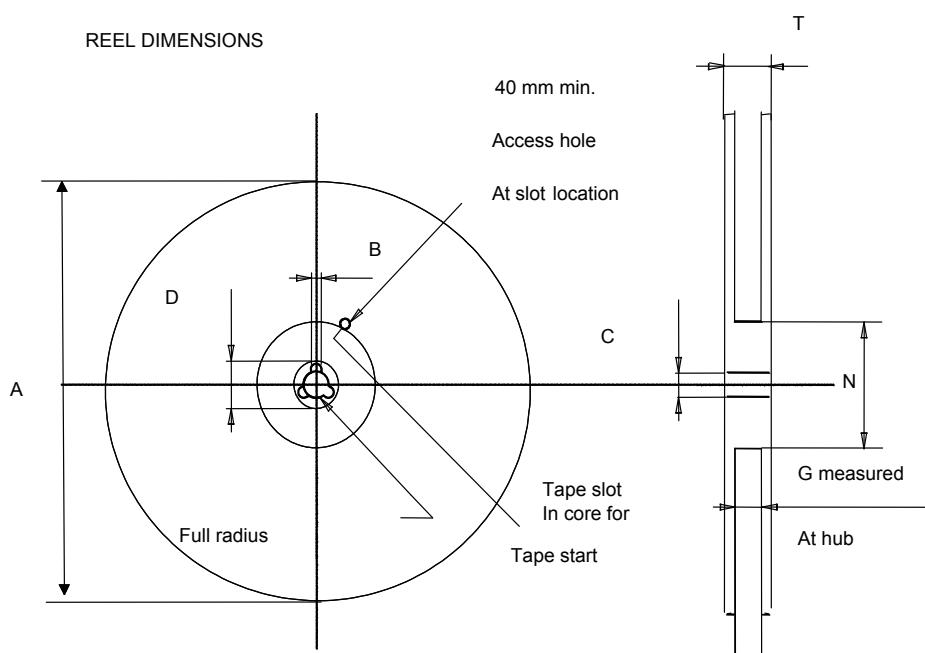


Table 9. Tape and reel mechanical data

| Tape | | | Reel | | |
|------|------|------|------|---------------|------|
| Dim. | mm | | Dim. | mm | |
| | Min. | Max. | | Min. | Max. |
| A0 | 10.5 | 10.7 | A | | 330 |
| B0 | 15.7 | 15.9 | B | 1.5 | |
| D | 1.5 | 1.6 | C | 12.8 | 13.2 |
| D1 | 1.59 | 1.61 | D | 20.2 | |
| E | 1.65 | 1.85 | G | 24.4 | 26.4 |
| F | 11.4 | 11.6 | N | 100 | |
| K0 | 4.8 | 5.0 | T | | 30.4 |
| P0 | 3.9 | 4.1 | | | |
| P1 | 11.9 | 12.1 | | Base quantity | 1000 |
| P2 | 1.9 | 2.1 | | Bulk quantity | 1000 |
| R | 50 | | | | |
| T | 0.25 | 0.35 | | | |
| W | 23.7 | 24.3 | | | |

Revision history

Table 10. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 01-Feb-2021 | 1 | First release. |
| 24-Jun-2021 | 2 | Modified $R_{DS(on)}$ max. on cover page. Modified Table 1. Absolute maximum ratings, Table 2. Thermal data, Table 4. On/off-state and Table 7. Source-drain diode. Updated Section 3 Test circuits. Modified Figure 21. Tape outline. Minor text changes. |

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